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# Investigation of the Dynamic Load Modulation of an Inverse Class-F Power Amplifier with an Adaptive Matching Network

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**Abstract**—This paper presents a 10 Watt gallium nitride (GaN) based inverse class-F power amplifier with dynamic load modulation. The designed power amplifier uses an adaptive output matching network, which is realized using MEMS switches (micro electro mechanical systems), for the enhancement of the power added efficiency over the dynamic output range. Through the load modulation achieved by the adaptive matching network an efficiency enhancement of approximately 30 pp (percentage point) at 10-dB-back-off at the drain of the transistor is achieved compared to a power amplifier without load modulation. Through the use of an *in situ* measurement approach in-depth investigations of the working principle of the realized amplifier and adaptive matching network are possible.

**Index Terms**—Adaptive matching network, efficiency enhancement, inverse class-F, load modulation, time domain measurement, power amplifier.

## I. INTRODUCTION

Simple power amplifier structures based on a single transistor can achieve their highest efficiency only at the maximum output power. For applications with variable output power, the power amplifier is less efficient when operated at lower output powers. One possible approach to enhance the efficiency is presented in [1], where a class-F power amplifier with a manually tuned matching network is introduced. The benefit of this approach is shown through the efficiency enhancement in the back-off range. A class-AB amplifier with an adaptive matching network for load modulation is presented, e.g., in [2]. Furthermore, a multi-mode-matching output network is described, e.g., in [3] and shows the application of RF-MEMS switches for the reconfiguration of a matching network for a GaN power amplifier.

In this contribution an adaptive matching network, based on MEMS, is integrated into an inverse class-F power amplifier for an efficiency enhancement over a large range of output power. Supplementary, an *in situ* measurement approach is used to measure the high frequency voltages and currents to calculate the actual load impedance seen at the transistor package plane for an in-depth investigation of the load modulation. First, the load modulation operation principle is described. The design of an inverse class-F power amplifier with an adaptive matching network is shown in Section III. In addition the embedding of a

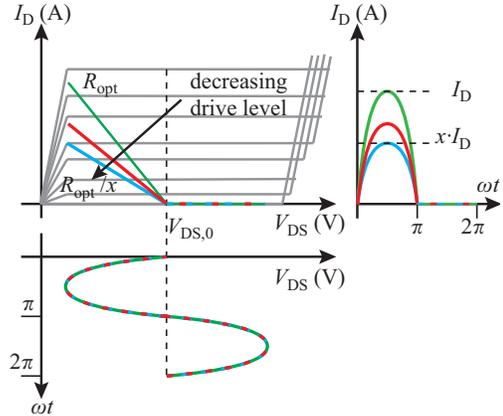


Fig. 1. Load line adaptation to achieve constant voltage swing.

directional coupler for the *in situ* measurement approach is described. Subsequently in Section IV, measurement results of the *in situ* measurement approach are presented proving the applicability of the proposed adaptive matching network for the load modulation.

## II. OPERATION PRINCIPLE OF THE LOAD MODULATION

In power amplifiers with a fixed matching network between transistor and load, the maximum efficiency is only achieved at the maximum power level [4]. In an amplifier with load modulation, e.g. the Doherty amplifier, the resistance  $R_{opt}$ , seen by the transistors internal current source, is increased by the factor  $1/x$  at lower power levels, whereby  $0 < x \leq 1$ . As a result the voltage swing is maximized at all output power levels, which is illustrated in Fig. 1 for the operation principle of a load modulated class-B amplifier.

In contrast to the voltage  $V_{DS}$  the current  $I_D$  is decreasing with increasing  $R_{opt}$  (cp. Fig. 1). The enhancement of the voltage  $V_{DS}$  to the maximal voltage swing for the corresponding  $R_{opt}$  is the reason of the efficiency enhancement in the back-off range.

## III. DESIGN OF AN INVERSE CLASS-F POWER AMPLIFIER WITH LOAD MODULATION

The transistor of an inverse class-F power amplifier operates as a saturated controlled current source with the optimal load  $R_{opt}$  at the internal current source. In order to approximate a square-wave current and a half



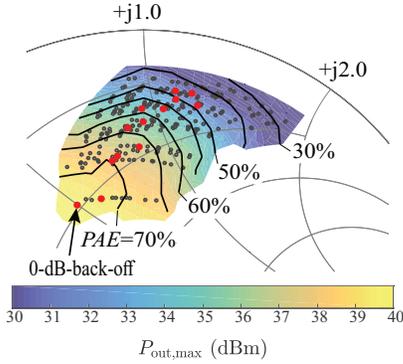


Fig. 6. Measured PAE and output power  $P_{out}$  depending on  $Z_{opt,A}$  for all matching states.

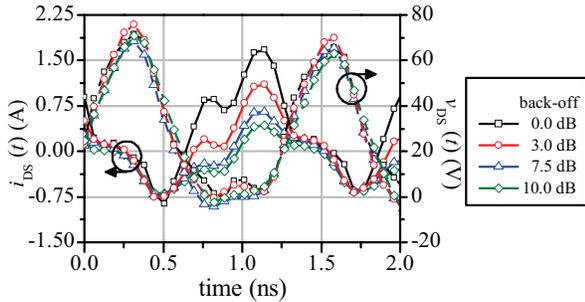


Fig. 7. Measured voltages and currents for various matching states in reference plane A.

are turned off), only the offset capacitors are used. Hence, the power gain  $G_P$  is  $\approx -0.5$  dB, which corresponds to a low insertion loss. For an increasing back-off range, higher capacitances are necessary, thus the appropriate MEMS switches have to be activated. Accordingly, the  $G_P$  decreases, respectively the losses increase with increasing back-off range. This explains the difference between the PAE-envelopes in Fig. 4. Nevertheless, the efficiency enhancement of the load modulated amplifier compared to the power amplifier with fixed matching network is increased in the reference plane B. The matching network still provides an optimization potential through the reduction of the insertion loss and therefore to further enhance the PAE over the back-off range in reference plane B.

The achieved load modulation can be further analyzed in Fig. 6. It depicts the maximal PAE in plane B (black isolines) as well as the corresponding output power levels (underlying heatmap) in dependence of the load impedance  $Z_{opt,A}$  (red and black dots), which is adjusted through the adaptive matching network. Illustrated this way the load line for maximal PAE is recognisable along the protrusions of the PAE isolines and the optimal matching states (red dots) can be chosen. Accordingly, the red dots also represent the matching states of the graphs in Fig. 4.

In addition, the effect of the load modulation can be evaluated from Fig. 7, where the measured high frequency voltages and currents for various matching states in reference plane A are presented. As it can be seen, the high frequency voltage has the same shape with the maximum

amplitude for the presented states. Furthermore, the high frequency current decreases for an increasing back-off range, which corresponds to the theory of Section II. The waveforms from Fig. 7 could be further de-embedded to the internal current source plane of the transistor to verify the inverse class-F operation [9].

With the realized adaptive matching network, an efficiency enhancement in the back-off region is shown in both reference planes. The use of the *in situ* measurement approach allows an in-depth study of complex amplifier topologies under operational conditions.

## V. CONCLUSION

This work introduces an inverse class-F power amplifier with an integrated *in situ* measurement capability under load modulation. Therefore, an adaptive inverse L matching network is realized, which is based on transmission lines and tunable capacitors. The tunability of the capacitors is achieved by using MEMS switches. The adaptive matching network performance is verified by measurements and exhibits an efficiency enhancement of 30 pp at 10-dB-back-off in the reference plane A. Furthermore, the time domain measurement approach provides the opportunity, to get knowledge about the high frequency voltages and currents at the transistor package plane under operational conditions. With this knowledge, the load modulation is verified and an impedance measurement for adjusting realized adaptive output matching networks becomes possible.

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